Applicant: Hiroto UCHIYAMA Attorney's Docket No.: 10830-076001 / A36-Serial No.: 10/047 524 137201M/MAN

Serial No.: 10/047,524 Filed: October 23, 2001

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REMARKS

Claims 3 and 4 are allowed.

Claims 1 and 2 are rejected as followed:

- * Claim 1 is rejected as anticipated by U.S. Patent No. 5,398,252 (Ohashi).
- * Claim 2 is rejected as unpatentable over the Ohashi patent in view of U.S. Patent No. 6,480,016 (Motoi et al.).

Claim 1 has been amended to recite "an alarm control portion for judging whether the alarm is to be displayed or not, on the basis of the permissible value calculated by the permissible value calculation portion and the number of continuous failures occurring in the measured IC." That feature is disclosed, for example, in the pending specification as follows:

Next, in Step S31, the number of continuous failures stored in the measured value memory 2C3 is compared with the permissible value stored in the permissible value memory 2C2. If the number of continuous failures stored in the measured value memory 2C3 does not exceed the permissible value stored in the permissible value memory 2C2 (No), the processing in the alarm control portion 2F is terminated. If the number of continuous failures stored in the measured value memory 2C3 exceeds the permissible value stored in the permissible value memory 2C2 (Yes), in Step S32, the alarm control portion 2F outputs an alarm display signal to the alarm display portion 4A, and the alarm display portion 4A displays an alarm.

(Page 10, line 24 – page 11, line 11)

Therefore, as recited in claim 1, determining whether the alarm is to be displayed or not is based at least on (i) the permissible value calculated by the permissible value calculation portion, and (ii) the number of continuous failures occurring in the measured IC.

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The Ohashi patent discloses an integrated circuit tester that includes a comparator 27 to compare the output from a device under test (DUT) 33 with expected patterns. The compared result is indicated in a display 31 so that failures can be observed.

The Motoi et al. Patent discloses a test system for a semiconductor integrated circuit. A comparator compares an output signal from the device with an expected value. That patent discloses different storages (*i.e.*, memories) for storing the input signal for testing the device and the expected signals.

Neither of the cited references discloses or suggests determining whether or not the alarm is to be displayed based, at least in part, on the criteria set forth in claim 1. At least for that reason, claim 1, as well as dependent claim 2, should be allowed.

Please apply any charges or credits to deposit account 06-1050.

Respectfully submitted,

Date: 4/6/05

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